

Closed Topic Search

Enter terms
Search

[Reset](#) Sort By: Close Date (descending)

- [Relevancy \(descending\)](#)
- [Title \(ascending\)](#)
- [Open Date \(descending\)](#)
- [Close Date \(ascending\)](#)
- [Release Date \(descending\)](#)

NOTE: The Solicitations and topics listed on this site are copies from the various SBIR agency solicitations and are not necessarily the latest and most up-to-date. For this reason, you should visit the respective agency SBIR sites to read the official version of the solicitations and download the appropriate forms and rules.

Displaying 1 - 10 of 13 results

Closed Topic Search

Published on SBIR.gov (<https://www.sbir.gov>)

1. DMEA15B-001: Optimized Scintillator for High Resolution X-ray Imaging at 9keV

Release Date: 04-24-2015 Open Date: 05-26-2015 Due Date: 06-24-2015 Close Date: 06-24-2015

Rapid Integrated Circuit (IC) inspection using x-ray microscopy requires novel x-ray scintillating materials with high efficiency and high spatial resolution. Current scintillator materials, such as Cesium Iodide (CsI), suffer from a trade-off between efficiency and spatial resolution. Novel materials with higher stopping power and light yields are necessary to address the stringent requirements o ...

STTR Defense Microelectronics Activity Department of Defense

2. 9.01: Advanced Manufacturing

Release Date: 03-09-2015 Open Date: 03-09-2015 Due Date: 05-15-2015 Close Date: 05-15-2015

Advanced Manufacturing is "a family of activities that (a) depend on the use and coordination of information, automation, computation, software, sensing, and networking, and/or (b) make use of cutting edge materials and emerging capabilities enabled by the physical and biological sciences, for example nanotechnology, chemistry, and biology. This involves both new ways to manufacture existing pro ...

SBIR National Institute of Standards and Technology Department of Commerce

3. 9.02: Climate Change and Clean Energy

Release Date: 03-09-2015 Open Date: 03-09-2015 Due Date: 05-15-2015 Close Date: 05-15-2015

Implementation of renewable energy and climate change related policies around the globe will require access to accurate, internationally recognized measurements and standards. These will be critical for both policy-making purposes as well as evaluating the impact of mitigation efforts. Such capabilities will be equally important for assessing the impact of energy and climate change policies on t ...

SBIR National Institute of Standards and Technology Department of Commerce

4. 9.03: Cybersecurity

Release Date: 03-09-2015 Open Date: 03-09-2015 Due Date: 05-15-2015 Close Date: 05-15-2015

Recognizing that the national and economic security of the United States depends on the reliable functioning of critical infrastructure, the President issued Executive Order 13636, Improving Critical Infrastructure Cybersecurity, in February 2013. It directed NIST to work with stakeholders to develop a voluntary framework - based on existing standards, guidelines, and practices - for reducing cy ...

SBIR National Institute of Standards and Technology Department of Commerce

5. [9.04: Health Care and Bioscience](#)

Release Date: 03-09-2015 Open Date: 03-09-2015 Due Date: 05-15-2015 Close Date: 05-15-2015

New medical diagnostic tests, improving the quality and cost-effectiveness of health care electronic records, reference materials for laboratory test methods, faster screening of promising vaccines, these are a few of the many areas where National Institute of Standards and Technology (NIST) research serves the needs of the bioscience and health care community. NIST collaborates extensively with o ...

SBIR National Institute of Standards and Technology Department of Commerce

6. [9.05: Technology Transfer](#)

Release Date: 03-09-2015 Open Date: 03-09-2015 Due Date: 05-15-2015 Close Date: 05-15-2015

This is the main research area, please review subtopics for a better description of available funding topics.

SBIR National Institute of Standards and Technology Department of Commerce

7. [DMEA13B-001: Electrochemical Micro-Capacitors Utilizing Carbon Nanostructures](#)

Release Date: 07-26-2013 Open Date: 08-26-2013 Due Date: 09-25-2013 Close Date: 09-25-2013

TECHNOLOGY AREAS: Materials/Processes, Electronics The technology within this topic is restricted under the International Traffic in Arms Regulation (ITAR), which controls the export and import of defense-related material and services. Offerors must disclose any proposed use of foreign nationals, their country of origin, and what tasks each would accomplish in the statement of work in accordan ...

STTR Department of Defense Defense Microelectronics Activity

8. [DMEA132-001: Miniaturized RF over Fiber](#)

Release Date: 04-24-2013 Open Date: 05-24-2013 Due Date: 06-26-2013 Close Date: 06-26-2013

OBJECTIVE: Design and prototype a capability to use fiber optic cable to simultaneously distribute power (i.e power over fiber) while providing full duplex information flow. The capability will allow miniature microwave system components to be distributed over a relatively long distance (i.e. 30 meters or more) via fiber optics. For example, a processing node (within a microwave system) provid ...

SBIR Defense Microelectronics Activity

9. [DMEA132-002: High Resolution Three-Dimensional Digital Reconstruction of Integrated Circuits](#)

Release Date: 04-24-2013 Open Date: 05-24-2013 Due Date: 06-26-2013 Close Date: 06-26-2013

OBJECTIVE: Develop a system for the accurate identification and analysis of semiconductor materials with integrated, high-resolution imaging capability for the three-dimensional digital reconstruction of integrated circuits (ICs). DESCRIPTION: As semiconductor geometries continue to diminish, so too does the applicability of traditional sample preparation tools. As the thickness of metal l ...

SBIR Defense Microelectronics Activity

10. [DMEA122-001: High Speed, High Resolution X-ray System for Inspecting Integrated Circuits](#)

Release Date: 04-24-2012 Open Date: 05-24-2012 Due Date: 06-27-2012 Close Date: 06-27-2012

OBJECTIVE: Develop an affordable x-ray microscope system for use in performing integrated circuit (IC) reverse engineering. DESCRIPTION: X-ray microscopy using a synchrotron as the x-ray source has been demonstrated to be an extremely valuable tool in the performance of high throughput integrated circuit evaluation and reverse engineering efforts. However, synchrotron x-ray sources are prohi ...

SBIR Defense Microelectronics Activity

- [1](#)
- [2](#)
- [Next](#)
- [Last](#)

```
jQuery(document).ready( function() { (function ($) { $('#edit-keys').attr("placeholder", 'Search Keywords'); $('#span.ext').hide(); })(jQuery); });
```